

WHAT IS CLAIMED IS:

1. A probe coming into contact with an electrode pad of a measurement object, comprising:

a connection terminal part integrally formed and connected to a substrate;

a contact part having a tapered configuration; and

a supporting part which supports the contact part, wherein the contact part extending from an end of the supporting part has a sectional configuration which shares at least one side face with the supporting part.

2. The probe according to claim 1, wherein the contact part is formed of an electrically conductive material having superior electric characteristics.

3. The probe according to claim 1, wherein the contact part is formed of a metal material having elasticity.